

June 2009

# FDB120N10

# N-Channel PowerTrench $^{\circledR}$ MOSFET 100V, 74A, 12m $\Omega$

#### **Features**

- $R_{DS(on)} = 9.7 \text{m}\Omega$  ( Typ.)@  $V_{GS} = 10 \text{V}$ ,  $I_D = 74 \text{A}$
- Fast Switching Speed
- · Low Gate Charge
- High Performance Trench Technology for Extremely Low  $R_{\mbox{\footnotesize{DS(on)}}}$
- High Power and Current Handling Capability
- RoHS Compliant



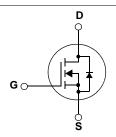
# **Description**

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

## **Application**

• DC to DC Converters / Synchronous Rectification





# MOSFET Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted

Symbol		Parameter		Ratings	Units
V <sub>DSS</sub>	Drain to Source Voltage			100	V
V <sub>GSS</sub>	Gate to Source Voltage			±20	V
	Drain Current - Continuous (T <sub>C</sub> = 25°C)			74	^
<sup>I</sup> D	Diam Current	- Continuous (T <sub>C</sub> = 100°C)		52	A
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	296	Α
E <sub>AS</sub>	Single Pulsed Avalanche	Energy	(Note 2)	198	mJ
dv/dt	Peak Diode Recovery dv/d	dt	(Note 3)	5.8	V/ns
D	Davier Dissipation	$(T_C = 25^{\circ}C)$		170	W
$P_{D}$	Power Dissipation	- Derate above 25°C		1.14	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Te	mperature Range		-55 to +175	°C
T <sub>L</sub>	Maximum Lead Temperate 1/8" from Case for 5 Seco	ure for Soldering Purpose, nds		300	°C

#### **Thermal Characteristics**

Symbol	Parameter	Ratings	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.88	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	-C/VV

Units

Max.

# **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDB120N10	FDB120N10	D2-PAK	330mm	24mm	800

**Test Conditions** 

Min.

Тур.

# Electrical Characteristics T<sub>C</sub> = 25°C unless otherwise noted Parameter

Off Chara	acteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V, T_C = 25^{\circ} C$	100	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, Referenced to 25°C	-	0.1	-	V/°C
ı	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 100V, V <sub>GS</sub> = 0V	-	-	1	μА
DSS	Zero Gate Voltage Drain Current	$V_{DS} = 100V, V_{GS} = 0V, T_{C} = 150^{\circ}C$	-	-	500	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	±100	nA

#### **On Characteristics**

Symbol

$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2.5	-	4.5	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 74A$	-	9.7	12	mΩ
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 10V, I_D = 74A$ (No	e 4) -	105	-	S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	$V_{DS} = 25V, V_{GS} = 0V$ f = 1MHz		4215	5605	pF
C <sub>oss</sub>	Output Capacitance			405	540	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 11/11/2	-	170	255	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V		-	66	86	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	$V_{DS} = 80 V I_{D} = 74 A$	-	26	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	V <sub>GS</sub> = 10V (Note 4, 5)	-	20	-	nC

### **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		-	27	64	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 50V, I_D = 74A$	-	105	220	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 10V$ , $R_{GEN} = 4.7\Omega$	-	39	88	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4, 5)	-	15	40	ns

#### **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current			-	-	74	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current			-	-	296	Α
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS} = 0V, I_{SD} = 74A$		-	-	1.3	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 74A		-	44	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$	(Note 4)	-	67	-	nC

- Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. L = 0.11mH, I  $_{AS}$  = 60A, V  $_{DD}$  = 50V, R  $_{G}$  = 25 $\!\Omega$ , Starting T  $_{J}$  = 25 $^{\circ}C$
- 3.  $I_{SD} \le 74 A$ , di/dt  $\le 200 A/\mu s$ ,  $V_{DD} \le BV_{DSS}$ , Starting  $T_J = 25^{\circ}C$
- 4. Pulse Test: Pulse width  $\leq 300 \mu s, \, \text{Duty Cycle} \leq 2\%$
- 5. Essentially Independent of Operating Temperature Typical Characteristics

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

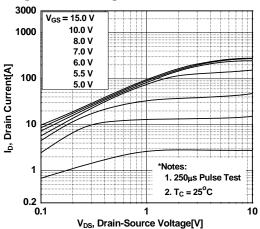


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

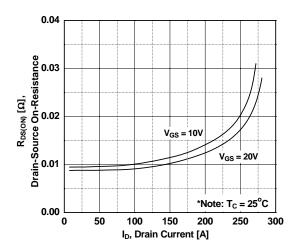


Figure 5. Capacitance Characteristics

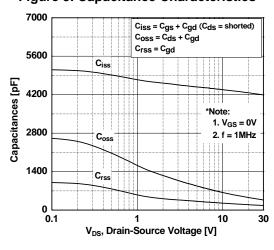


Figure 2. Transfer Characteristics

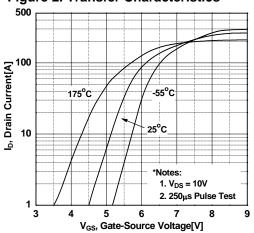
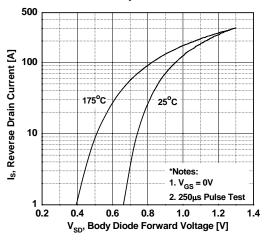
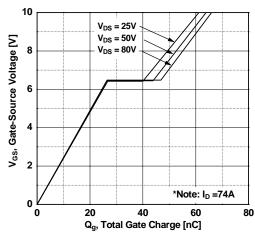


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature



**Figure 6. Gate Charge Characteristics** 



# **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

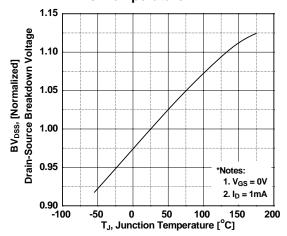


Figure 9. Maximum Safe Operating Area

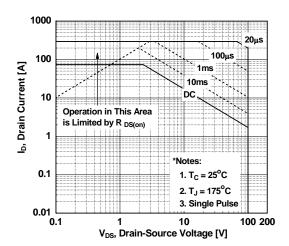


Figure 8. On-Resistance Variation vs. Temperature

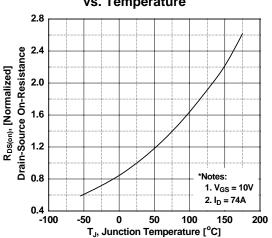


Figure 10. Maximum Drain Current vs. Case Temperature

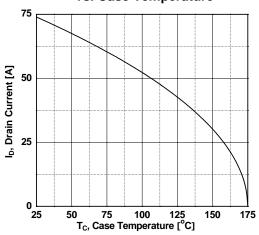
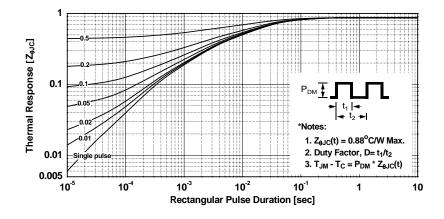
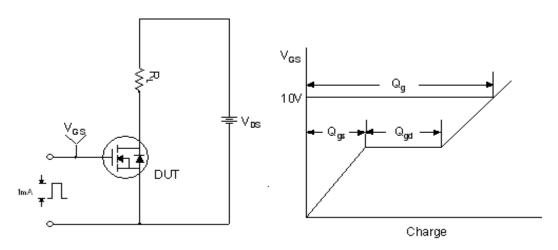


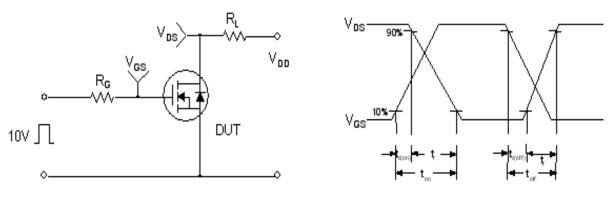
Figure 11. Transient Thermal Response Curve



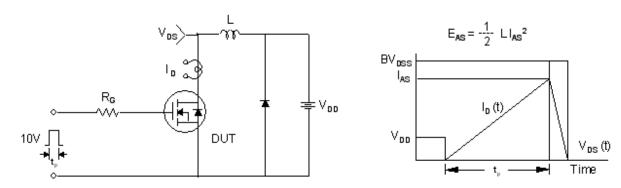
### **Gate Charge Test Circuit & Waveform**



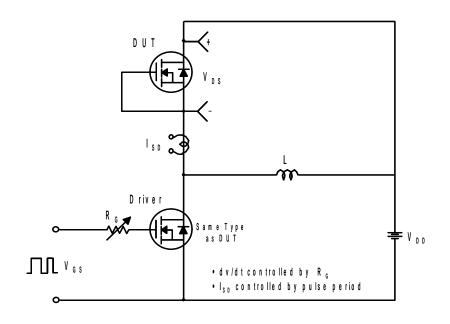
#### **Resistive Switching Test Circuit & Waveforms**

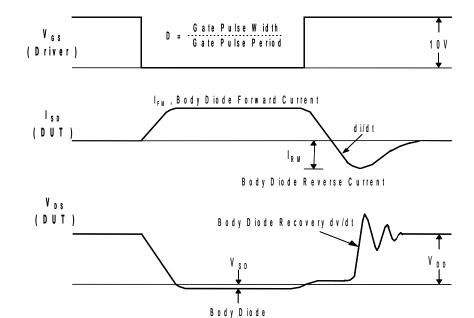


**Unclamped Inductive Switching Test Circuit & Waveforms** 



#### Peak Diode Recovery dv/dt Test Circuit & Waveforms

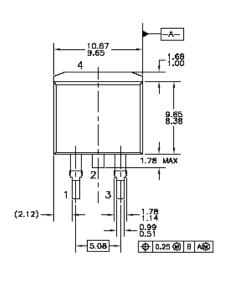


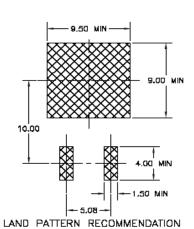


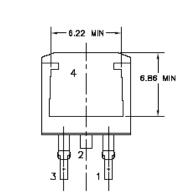
Forward Voltage Drop

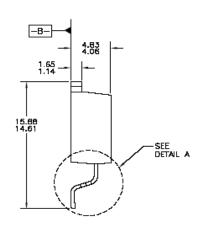
### **Mechanical Dimensions**

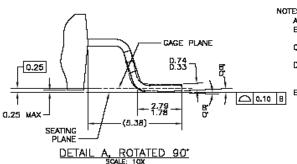
# D2-PAK











- NOTES: UNLESS OTHERWISE SPECIFIED

  A) ALL DIMENSIONS ARE IN MILLIMETERS.

  B) REFERENCE JEDEC, TO—263, ISSUE D,
  VARIATION AB, DATED JULY 2003.

  C) DIMENSIONING AND TOLERANCING PER
  ANSI Y14.5M 1982.

  D) LOCATION OF THE PIN HOLE MAY VARY
  (LOWER LEFT CORNER, LOWER CENTER
  AND CENTER OF THE PACKAGE).

  B E) PRESENCE OF TRIMMED CENTER LEAD
  IS OPTIONAL.

TO283AD2REVD

Dimensions in Millimeters





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